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FDW2507NZ

Common Drain N-Channel 2.5V specified PowerTrench® MOSFET

General Description

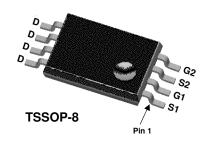
This monolithic common drain N-Channel MOSFET has been designed using Fairchild Semiconductor's advanced PowerTrench process to optimize the $R_{\rm DS(ON)}$ @ $V_{\rm GS}=2.5v$ on special TSSOP-8 lead frame with all the drains on one side of the package.

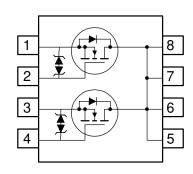
Applications

• Li-Ion Battery Pack

Features

- 7.5 A, 20 V $R_{DS(ON)} = 19 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$ $R_{DS(ON)} = 23 \text{ m}\Omega$ @ $V_{GS} = 2.5 \text{ V}$
- Isolated source and drain pins
- ESD protection diode (note 3)
- High performance trench technology for extremely low $R_{DS(ON)}$ @ V_{GS} = 2.5 V
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	7.5	Α
	- Pulsed		30	
P _D	Power Dissipation for Single Operation	(Note 1a)	1.6	W
		(Note 1b)	1.1	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	77	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	114	°C/W

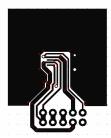
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
2507NZ	FDW2507NZ	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	20			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			10	μΑ
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$			-10	μΑ
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	0.6	0.8	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		4		mV/°C
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$\label{eq:VGS} \begin{array}{lll} V_{GS} = 4.5 \ V, & I_D = 7.5 \ A \\ V_{GS} = 2.5 \ V, & I_D = 6.8 \ A \\ V_{GS} = 4.5 \ V, I_D = 7.5 \ A, \ T_J = 125^{\circ}C \end{array}$		15 17 20	19 23 27	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	30			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 7.5 \text{ A}$		31		S
Dynamic	Characteristics	•				
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		2152		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		512		pF
C _{rss}	Reverse Transfer Capacitance			263		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		12	22	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		13	23	ns
t _{d(off)}	Turn-Off Delay Time			35	56	ns
t _f	Turn-Off Fall Time			19	34	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 7.5 \text{ A},$		20	28	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 4.5 \text{ V}$		3		nC
Q _{gd}	Gate-Drain Charge	7		5		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings	•	•	•	
Is	Maximum Continuous Drain-Source	•			1.3	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ (Note 2)		0.6	1.2	V
t _{rr}	Diode Reverse Recovery Time	$I_F = 7.5A$		26		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$ (Note 2)		21		nC

Notes

 R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 77°C/W when mounted on a 1in² pad of 2 oz copper

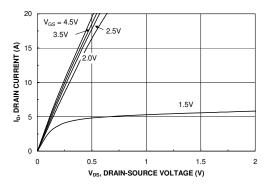


b) 114°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

- 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

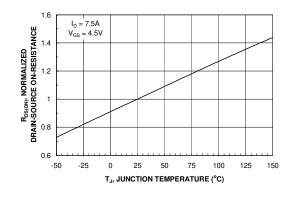
Typical Characteristics



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Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



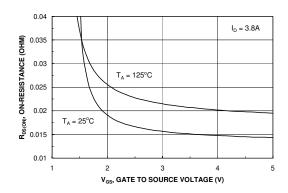
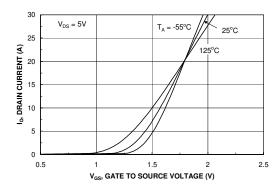


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



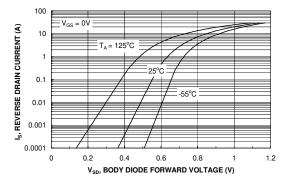
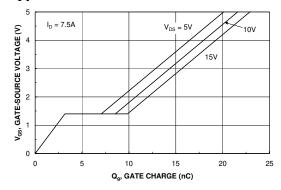


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



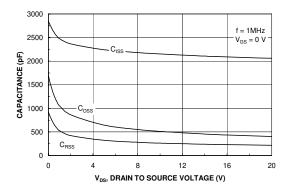
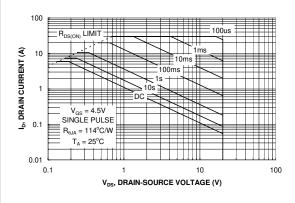


Figure 7. Gate Charge Characteristics.





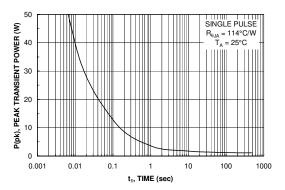


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

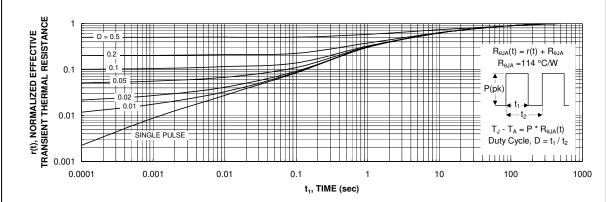


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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